

ENSC Batch No. \_\_\_\_\_ Wafers Started \_\_\_\_\_ Date \_\_\_\_\_  
 Material \_\_\_\_\_ Orientation \_\_\_\_\_ Size \_\_\_\_\_ Thickness \_\_\_\_\_  
 Resistivity \_\_\_\_\_ Type \_\_\_\_\_  
 Wafer Vendor \_\_\_\_\_ Vendor Batch # \_\_\_\_\_ SFU P.O. \_\_\_\_\_

Process Step #	Process Conditions	Oper & Wafer #	Comments
_____A	<b>Aluminum Etch to endpoint</b> Transene A1 aluminum etchant. Occasional agitation. Temp = 50C. Etch rate = 100 A/sec @ 50C. Calculate etch time as a guide, but determine endpoint by eye. Inspect for endpoint at Step D.		
_____B	<b>DI Water Rinse</b> > 5 min in running DI water		
_____C	<b>Dry</b> Do not spin. Resist contaminates chuck. Blow dry with dry N2. Bake briefly in soft bake oven if required.		
_____D	<b>Inspect</b> Microscope with yellow light and measurement capability. Ensure etch complete. Etch further if needed. Measure features if required.		<u>Measurement optional if required.</u>
_____E	<b>Photoresist Strip</b> Soak in room temp acetone until resist is dissolved. Soak in fresh acetone for a further 1-2 min.		
_____F	<b>DI Water Rinse</b> >10 minutes in running DI water		
_____G	<b>Dry</b> Spin at max RPM until dry (false colours disappear). Check back for water. Repeat spin and/or blow dry with dry N2 if necessary.		
_____H	<b>Inspect</b> Microscope with measurement capability. Inspect for remnant resist. Repeat strip if necessary. Measure features if required.		<u>Measurement optional if required.</u> Remnant resist may appear as fine films or hair like structures.